

Search Notes

Application/Control No.

10/753,976

Examiner

John F. Ramirez

Applicant(s)/Patent under
Reexamination

LIEW ET AL.

Art Unit

3737

SEARCHED

| Class | Subclass | Date | Examiner |
|---------|----------|------------|----------|
| UPDATED | | 11/29/2006 | JFR |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |

INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|------|----------|
| | | | |
| | | | |
| | | | |
| | | | |

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|---------|------------|------|
| UPDATED | 11/29/2006 | JFR |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |